

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Spirox Corporation/National Tsing Hua University
Title: DIAGONAL TESTING METHOD FOR FLASH MEMORIES Express Mail No. EV 126287357US
Serial No.: Not assigned Date of Mailing: June 24, 2003
Filing Date: June 24, 2003

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Mail Stop: Patent Application

Sir:

Applicant assignee's undersigned attorneys, who prepared the above-identified application, are aware of the references listed on the attached Form PTO-1449, copies of which are enclosed herewith, and which are relevant to said application.

Respectfully submitted,

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
		404800	Not assigned
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT	
		Spirox Corporation	
	FILING DATE	GROUP	
	June 24, 2003	Not assigned	

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AM							
AN							
AO							
AP							
AQ							

OTHER PRIOR ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

AR	Yeh et. al, "Flash Memory Built-In Self Test Using March-Like Algorithms"
AS	Mohammad et al., "Testing Flash Memories", (pgs. 406-411), January 2000
AT	Mohammad et al., "Flash Memory Disturbances: Modeling and Test" (pgs. 1- 9)

"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your next communication to applicant."